

Notice of References Cited

Application/Control No.		Applicant(s)/Patent Under Reexam
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Examiner	Art Unit	
B. William Baumeister	2815	Page 1 of 1

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NON-PATENT DOCUMENTS

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¹A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a). ²Dates in MM-YYYY format are publication dates. ²Classifications may be U.S. or foreign.